



Scanning electron micrograph, at 200x, of microflaking on a chert edge. The SEM allows a great depth of field to be examined at one time and is best for illustrating small microflakes. Regularly-sized hinge- and step-terminated microflakes, as seen here, are rarely found consistently along a lithic edge unless the edge has been used, and the spatial continuity of microflakes along an edge is one of the variables recorded in this study as an interpretive guide.

**Appendix B, Figure B8.**  
**Scanning Electron Micrograph of Microflaking.**